

Hex Inverter

The MC74VHCT04A is an advanced high speed CMOS inverter fabricated with silicon gate CMOS technology. It achieves high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

The internal circuit is composed of three stages, including a buffer output which provides high noise immunity and stable output. The inputs tolerate voltages up to 7V, allowing the interface of 5V systems to 3V systems.

The VHCT inputs are compatible with TTL levels. This device can be used as a level converter for interfacing 3.3V to 5.0V, because it has full 5V CMOS level output swings.

The VHCT04A input structures provide protection when voltages between 0V and 5.5V are applied, regardless of the supply voltage. The output structures also provide protection when V_{CC} = 0V. These input and output structures help prevent device destruction caused by supply voltage – input/output voltage mismatch, battery backup, hot insertion, etc.

- High Speed: $t_{PD} = 4.7 \text{ns}$ (Typ) at $V_{CC} = 5 \text{V}$
- Low Power Dissipation: $I_{CC} = 2\mu A$ (Max) at $T_A = 25$ °C
- TTL-Compatible Inputs: $V_{IL} = 0.8V$; $V_{IH} = 2.0V$
- Power Down Protection Provided on Inputs and Outputs
- Balanced Propagation Delays
- Designed for 4.5V to 5.5V Operating Range
- Low Noise: VOLP = 1.0V (Max)
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 300mA
- ESD Performance: HBM > 2000V; Machine Model > 200V
- Chip Complexity: 48 FETs or 12 Equivalent Gates
- These devices are available in Pb-free package(s). Specifications herein
 apply to both standard and Pb-free devices. Please see our website at
 www.onsemi.com for specific Pb-free orderable part numbers, or
 contact your local ON Semiconductor sales office or representative.

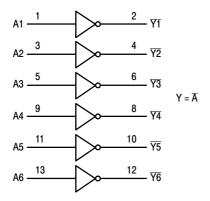


Figure 1. Logic Diagram

MC74VHCT04A



D SUFFIX 14-LEAD SOIC PACKAGE CASE 751A-03



DT SUFFIX 14-LEAD TSSOP PACKAGE CASE 948G-01



M SUFFIX 14-LEAD SOIC EIAJ PACKAGE CASE 965-01

ORDERING INFORMATION

MC74VHCTXXAD SOIC
MC74VHCTXXADT TSSOP
MC74VHCTXXAM SOIC EIAJ

FUNCTION TABLE

Inputs	Outputs
Α	Y
L	Н
Н	L

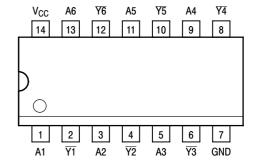


Figure 2. Pinout: 14-Lead Packages (Top View)

MAXIMUM RATINGS*

Symbol	Parameter	1	Value	Unit
V _{CC}	DC Supply Voltage	- 0.5 to + 7.0	V	
V _{in}	DC Input Voltage	- 0.5 to + 7.0	٧	
V _{out}	DC Output Voltage	- 0.5 to + 7.0 - 0.5 to V _{CC} + 0.5	V	
I _{IK}	Input Diode Current	- 20	mA	
I _{OK}	Output Diode Current (V _{OUT} < 0	GND; V _{OUT} > V _{CC})	±[2 0	mA
l _{out}	DC Output Current, per Pin		± [2 5	mA
I _{CC}	DC Supply Current, V _{CC} and GI	ND Pins	±[5 0	mA
P _D	Power Dissipation in Still Air,	SOIC Packages† TSSOP Package†	500 450	mW
T _{stg}	Storage Temperature		- 65 to + 150	°C

^{*} Absolute maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute-maximum-rated conditions is not implied.

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range GND \leq (V_{in} or V_{out}) \leq V_{CC} .

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or $V_{\rm CC}$). Unused outputs must be left open.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V _{CC}	DC Supply Voltage	4.5	5.5	V
V _{in}	DC Input Voltage	0	5.5	V
V _{out}	DC Output Voltage V _{CC} = 0 High or Low State	0 0	5.5 V _{CC}	٧
T _A	Operating Temperature	- 40	+ 85	°C
t _r , t _f	Input Rise and Fall Time V _{CC} =5.0V ±0.5V	0	20	ns/V

DC ELECTRICAL CHARACTERISTICS

			v _{cc}		T _A = 25°C	;	T _A = -4	0 to 85°C	
Symbol	Parameter	Test Conditions	v	Min Typ		Max	Min Max		Unit
V _{IH}	Minimum High-Level Input Voltage		4.5 to 5.5	2.0			2.0		V
V _{IL}	V _{IL} Maximum Low–Level Input Voltage		4.5 to 5.5			0.8		0.8	V
V _{OH}	Minimum High-Level	I _{OH} = - 50μA	4.5	4.4	4.5		4.4		V
Output Voltage $V_{in} = V_{IH}$ or V_{IL}		I _{OH} = - 8mA	4.5	3.94			3.80		
V _{OL} Maximum Low-Level Output Voltage V _{in} = V _{IH} or V _{IL}		I _{OL} = 50μA	4.5		0.0	0.1		0.1	V
		I _{OL} = 8mA	4.5			0.36		0.44	
I _{in} Maximum Input V _{in} = 5.5 V or GND Leakage Current		V _{in} = 5.5 V or GND	0 to 5.5			±[0.1		±[1.0	μΑ
Icc	I _{CC} Maximum Quiescent V _{in} = V _{CC} or GND Supply Current		5.5			2.0		20.0	μΑ
Гсст	I_{CCT} Quiescent Supply Per Input: $V_{IN} = 3.4V$ Other Input: V_{CC} or GND		5.5			1.35		1.50	mA
I _{OPD}	, , ,		0			0.5		5.0	μΑ

[†]Derating — SOIC Packages: – 7 mW/°C from 65° to 125°C TSSOP Package: – 6.1 mW/°C from 65° to 125°C

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3.0 \text{ns}$)

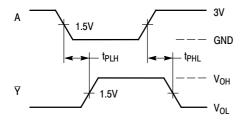
		T _A = 25°C		T _A = - 40 to 85°C					
Symbol	Parameter	Test Condi	tions	Min	Тур	Max	Min	Max	Unit
t _{PLH} , t _{PHL}	Maximum Propagation Delay, A to Y	$V_{CC} = 5.0 \pm 0.5 V$	$C_L = 15pF$ $C_L = 50pF$		4.7 5.5	6.7 7.7	1.0 1.0	7.5 8.5	ns
C _{in}	Maximum Input Capacitance				4	10		10	pF

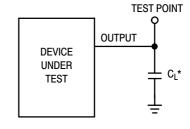
		Typical @ 25°C, V _{CC} = 5.0V	
C_{PD}	Power Dissipation Capacitance (Note 1)	11	pF

^{1.} C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \cdot V_{CC} \cdot f_{in} + I_{CC}/6$ (per buffer). C_{PD} is used to determine the no–load dynamic power consumption; $P_D = C_{PD} \cdot V_{CC}^2 \cdot f_{in} + I_{CC} \cdot V_{CC}$.

NOISE CHARACTERISTICS (Input t_{r} = t_{f} = 3.0ns, C_{L} = 50pF, V_{CC} = 5.0V)

		T _A = 25°C		
Symbol	Characteristic	Тур	Max	Unit
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	0.8	1.0	V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	-0.8	-1.0	V
V _{IHD}	Minimum High Level Dynamic Input Voltage		2.0	V
V _{ILD}	Maximum Low Level Dynamic Input Voltage		0.8	V





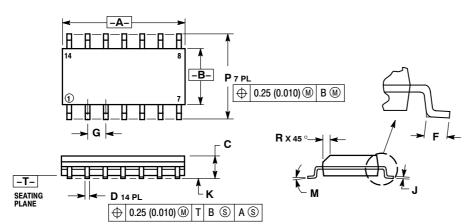
*Includes all probe and jig capacitance

Figure 3. Switching Waveforms

Figure 4. Test Circuit

OUTLINE DIMENSIONS

D SUFFIX SOIC-14 **CASE 751A-03 ISSUE F**

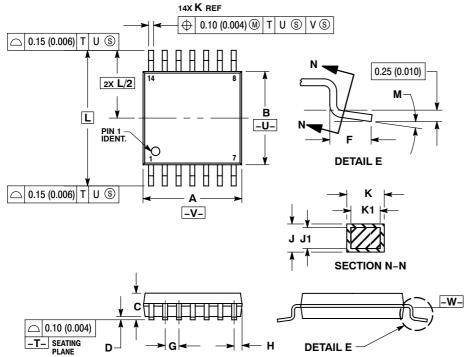


- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
 4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
 5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIN	IETERS	INC	HES			
DIM	MIN	MAX	MIN	MAX			
Α	8.55	8.75	0.337	0.344			
В	3.80	4.00	0.150	0.157			
С	1.35	1.75	0.054	0.068			
D	0.35	0.49	0.014	0.019			
F	0.40	1.25	0.016	0.049			
G	1.27	BSC	0.050 BSC				
J	0.19	0.25	0.008	0.009			
K	0.10	0.25	0.004	0.009			
M	0 °	7°	0°	7°			
P	5.80	6.20	0.228	0.244			
R	0.25	0.50	0.010	0.019			

OUTLINE DIMENSIONS

DT SUFFIX TSSOP CASE 948G-01 ISSUE 0



- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ANSI Y14,5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

 3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.

 4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.

 5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION ALLOWABLE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.

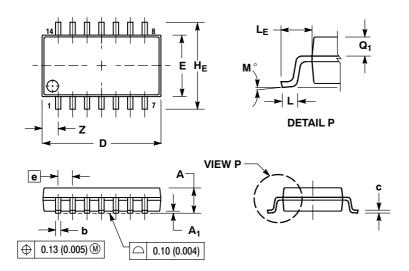
 6. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.

 7. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

	MILLIN	IETERS	INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	4.90	5.10	0.193	0.200	
В	4.30	4.50	0.169	0.177	
C		1.20		0.047	
D	0.05	0.15	0.002	0.006	
F	0.50	0.75	0.020	0.030	
G	0.65	BSC	0.026	6 BSC	
Н	0.50	0.60	0.020	0.024	
J	0.09	0.20	0.004	0.008	
J1	0.09	0.16	0.004	0.006	
K	0.19	0.30	0.007	0.012	
K1	0.19	0.25	0.007	0.010	
L	6.40 BSC		0.252		
M	0°	8°	0°	8°	

OUTLINE DIMENSIONS

M SUFFIX SO-14 **CASE 965-01 ISSUE 0**



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI
- 1. DIMENSIONING AND TOLEHANGING FER AND Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. DIMENSIONS DAND E DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS AND ARE MEASURED AT THE PARTING LINE. MOLD FLASH OR PROTRUSIONS SHALL NOT EXCEED 0.15 (0.006) DED SIDE.
- PROTRUSIONS SHALL NOT EXCEED 0.15 (0.006)
 PER SIDE.

 4. TERMINAL NUMBERS ARE SHOWN FOR
 REFERENCE ONLY.

 5. THE LEAD WIDTH DIMENSION (b) DOES NOT
 INCLUDE DAMBAR PROTRUSION. ALLOWABLE
 DAMBAR PROTRUSION SHALL BE 0.08 (0.003)
 TOTAL IN EXCESS OF THE LEAD WIDTH
 DIMENSION AT MAXIMUM MATERIAL CONDITION.
 DAMBAR CANNOT BE LOCATED ON THE LOWER
 RADILIS OR THE FOOT MINIMUM SPACE RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSIONS AND ADJACENT LEAD TO BE 0.46 (0.018).

	MILLIN	IETERS	INC	HES			
DIM	MIN	MAX	MIN	MAX			
Α		2.05		0.081			
A ₁	0.05	0.20	0.002	0.008			
b	0.35	0.50	0.014	0.020			
С	0.18	0.27	0.007	0.011			
D	9.90	10.50	0.390	0.413			
Е	5.10	5.45	0.201	0.215			
е	1.27	BSC	0.050	BSC			
HE	7.40	8.20	0.291	0.323			
0.50	0.50	0.85	0.020	0.033			
ш	1.10	1.50	0.043	0.059			
M	0 °	10 °	0 °	10°			
Q ₁	0.70	0.90	0.028	0.035			
Z		1.42		0.056			

Notes

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